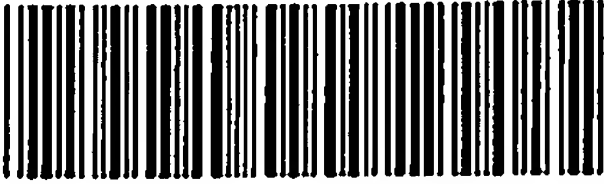


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/644,782	KANEKO ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	John P. Sheehan	1742	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
P.G. Pub		4/28/06	JPS

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	11/22/2005	JPS
PALM Inventor Name Search	11/22/2005	JPS